

1. Record Nr.	UNISALENTO991001839569707536
Autore	American Mathematical Society.Short Course <2011 : New Orleans, Louisiana>
Titolo	Evolutionary game dynamics : American Mathematical Society Short Course, January 4-5, 2011, New Orleans, Louisiana / Karl Sigmund, editor
Pubbl/distr/stampa	Providence, R. I. : American Mathematical Society, c2011
ISBN	9780821853269
Descrizione fisica	viii, 175 p. : ill. ; 27 cm
Collana	Proceedings of symposia in applied mathematics, 0160-7634 ; 69. AMS short course lecture notes
Classificazione	AMS 91A22 LC QA269.A465
Altri autori (Persone)	Sigmund, Karlauthor
Disciplina	519.3
Soggetti	Game theory - Congresses
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Nota di bibliografia	Includes bibliographical references and index

2. Record Nr.	UNINA9910831162003321
Titolo	Advances in speckle metrology and related techniques [[electronic resource] /] / edited by Guillermo H. Kaufmann
Pubbl/distr/stampa	Weinheim, : Wiley-VCH Verlag, c2011
ISBN	3-527-63387-1 1-283-14068-3 9786613140685 3-527-63385-5 3-527-63386-3
Edizione	[4th ed.]
Descrizione fisica	1 online resource (329 p.)
Altri autori (Persone)	KaufmannGuillermo H
Disciplina	621.36
Soggetti	Speckle metrology Optical measurements
Lingua di pubblicazione	Inglese
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Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Advances in Speckle Metrology and Related Techniques; Contents; Preface; List of Contributors; 1 Radial Speckle Interferometry and Applications; 2 Depth-Resolved Displacement Field Measurement; 3 Single-Image Interferogram Demodulation; 4 Phase Evaluation in Temporal Speckle Pattern Interferometry Using Time-Frequency Methods; 5 Optical Vortex Metrology; 6 Speckle Coding for Optical and Digital Data Security Applications; Index
Sommario/riassunto	Speckle metrology includes various optical techniques that are based on the speckle fields generated by reflection from a rough surface or by transmission through a rough diffuser. These techniques have proven to be very useful in testing different materials in a non-destructive way. They have changed dramatically during the last years due to the development of modern optical components, with faster and more powerful digital computers, and novel data processing approaches. This most up-to-date overview of the topic describes new techniques developed in the field of speckle metrology over t